



NSAI
Standards

Irish Standard
I.S. EN 60749-5:2017

Semiconductor devices - Mechanical and climatic test methods - Part 5: Steady-state temperature humidity bias life test

I.S. EN 60749-5:2017

Incorporating amendments/corrigenda/National Annexes issued since publication:

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NSAI
1 Swift Square,
Northwood, Santry
Dublin 9

T +353 1 807 3800
F +353 1 807 3838
E standards@nsai.ie
W NSAI.ie

Sales:
T +353 1 857 6730
F +353 1 857 6729
W standards.ie

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National Foreword

I.S. EN 60749-5:2017 is the adopted Irish version of the European Document EN 60749-5:2017, Semiconductor devices - Mechanical and climatic test methods - Part 5: Steady-state temperature humidity bias life test

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EUROPEAN STANDARD

EN 60749-5

NORME EUROPÉENNE

EUROPÄISCHE NORM

July 2017

ICS 31.080.01

Supersedes EN 60749-5:2003

English Version

**Semiconductor devices - Mechanical and climatic test methods -
Part 5: Steady-state temperature humidity bias life test
(IEC 60749-5:2017)**

Dispositifs à semiconducteurs - Méthodes d'essais
mécaniques et climatiques - Partie 5: Essai continu de
durée de vie sous température et humidité avec polarisation
(IEC 60749-5:2017)

Halbleiterbauelemente - Mechanische und klimatische
Prüfverfahren - Teil 5: Lebensdauerprüfung bei konstanter
Temperatur und Feuchte unter elektrischer Beanspruchung
(IEC 60749-5:2017)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

EN 60749-5:2017

European foreword

The text of document 47/2367/FDIS, future edition 2 of IEC 60749-5, prepared by IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 60749-5:2017.

The following dates are fixed:

- latest date by which the document has to be (dop) 2018-02-15
implemented at national level by
publication of an identical national
standard or by endorsement
- latest date by which the national (dow) 2020-05-15
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This document supersedes EN 60749-5:2003.

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Annex ZA

(normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60749-4	-	Semiconductor devices - Mechanical and climatic test methods - Part 4: Damp heat, steady state, highly accelerated stress test (HAST)	EN 60749-4	-

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IEC 60749-5

Edition 2.0 2017-04

INTERNATIONAL STANDARD

**Semiconductor devices – Mechanical and climatic test methods –
Part 5: Steady-state temperature humidity bias life test**



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IEC Central Office
3, rue de Varembe
CH-1211 Geneva 20
Switzerland

Tel.: +41 22 919 02 11
Fax: +41 22 919 03 00
info@iec.ch
www.iec.ch

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IEC 60749-5

Edition 2.0 2017-04

INTERNATIONAL STANDARD

**Semiconductor devices – Mechanical and climatic test methods –
Part 5: Steady-state temperature humidity bias life test**

INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

SEMICONDUCTOR DEVICES – MECHANICAL AND CLIMATIC TEST METHODS –

Part 5: Steady-state temperature humidity bias life test

FOREWORD

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International Standard IEC 60749-5 has been prepared by IEC technical committee 47: Semiconductor devices.

This second edition cancels and replaces the first edition published in 2003. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) correction of an error in an equation;
- b) inclusion of notes for guidance;
- c) clarification of the applicability of test conditions.

The text of this International Standard is based on the following documents:

FDIS	Report on voting
47/2367/FDIS	47/2383/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 60749 series, published under the general title *Semiconductor devices – Mechanical and climatic test methods*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

SEMICONDUCTOR DEVICES – MECHANICAL AND CLIMATIC TEST METHODS –

Part 5: Steady-state temperature humidity bias life test

1 Scope

This part of IEC 60749 provides a steady-state temperature and humidity bias life test for the purpose of evaluating the reliability of non-hermetic packaged solid-state devices in humid environments.

This test method is considered destructive.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60749-4, *Semiconductor devices – Mechanical and climatic test methods – Part 4: Damp heat, steady-state, highly accelerated stress test (HAST)*

3 Terms and definitions

No terms and definitions are listed in this document.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>

4 General

This test employs conditions of temperature, humidity and bias which accelerate the penetration of moisture through the external protective material (encapsulant or seal) or along the interface between the external protective material and the metallic conductors which pass through it.

Where both this steady-state, humidity bias test and the damp heat, highly accelerated stress test (HAST) of IEC 60749-4 are performed, the results of this 85 °C/85 % RH steady-state test will take priority over the results of the HAST test, which is an accelerated test designed to activate the same failure mechanisms.

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